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 Package Options Include Plastic Small-Outline (D), Thin Shrink
Small-Outline (PW), and Ceramic Flat (W)
Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J)
300-mil DIPs

#### description

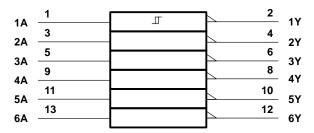
These Schmitt-trigger devices contain six independent inverters. They perform the Boolean function  $Y = \overline{A}$  in positive logic.

The SN54HC14 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74HC14 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE (each inverter)

INPUT A	OUTPUT Y
Н	L
L	Н

#### logic symbol†



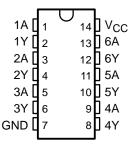
<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, J, N, PW, and W packages.

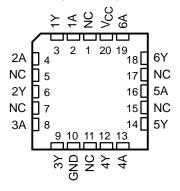
#### logic diagram (positive logic)



#### SN54HC14 . . . J OR W PACKAGE SN74HC14 . . . D, N, OR PW PACKAGE (TOP VIEW)



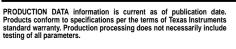
### SN54HC14...FK PACKAGE (TOP VIEW)



NC - No internal connection



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





#### SN54HC14, SN74HC14 HEX SCHMITT-TRIGGER INVERTERS

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#### absolute maximum ratings over operating free-air temperature range†

Supply voltage range, V <sub>CC</sub>	0.5 V to 7 V
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ ) (see Note 1)	±20 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>CC</sub> ) (see Note	1) ±20 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	±25 mA
Continuous current through V <sub>CC</sub> or GND	±50 mA
Package thermal impedance, $\theta_{JA}$ (see Note 2): D package	
N package	
PW packag	e 170°C/W
Storage temperature range, T <sub>stg</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

#### recommended operating conditions

			S	SN54HC14			SN74HC14			
			MIN	NOM	NOM MAX MIN NOM			MAX	UNIT	
VCC	Supply voltage		2	5	6	2	5	6	V	
	V <sub>CC</sub> = 2 V	1.5			1.5					
٧ıH	High-level input voltage	$V_{CC} = 4.5 \text{ V}$	3.15			3.15			V	
		V <sub>CC</sub> = 6 V	4.2			4.2				
		V <sub>CC</sub> = 2 V	0		0.5	0		0.5		
VIL	Low-level input voltage	V <sub>CC</sub> = 4.5 V	0		1.35	0		1.35	V	
		V <sub>CC</sub> = 6 V	0		1.8	0		1.8		
٧ı	Input voltage		0		VCC	0		VCC	V	
٧o	Output voltage		0		VCC	0		VCC	V	
T <sub>A</sub>	Operating free-air temperature		-55		125	-40		85	°C	



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## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		V	T <sub>A</sub> = 25°C		SN54HC14		SN74HC14		UNIT	
PARAMETER			v <sub>CC</sub>	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
			2 V	1.9	1.998		1.9		1.9		
		I <sub>OH</sub> = -20 μA	4.5 V	4.4	4.499		4.4		4.4		V
Voн	VI = VIH or VIL		6 V	5.9	5.999		5.9		5.9		
		$I_{OH} = -4 \text{ mA}$	4.5 V	3.98	4.3		3.7		3.84		
		$I_{OH} = -5.2 \text{ mA}$	6 V	5.48	5.8		5.2		5.34		
			2 V		0.002	0.1		0.1		0.1	
		I <sub>OL</sub> = 20 μA	4.5 V		0.001	0.1		0.1		0.1	V
V <sub>OL</sub>	VI = VIH or VIL		6 V		0.001	0.1		0.1		0.1	
		I <sub>OL</sub> = 4 mA	4.5 V		0.17	0.26		0.4		0.33	
		I <sub>OL</sub> = 5.2 mA	6 V		0.15	0.26		0.4		0.33	
			2 V	0.7	1.2	1.5	0.7	1.5	0.7	1.5	
V <sub>T+</sub>			4.5 V	1.55	2.5	3.15	1.55	3.15	1.55	3.15	V
			6 V	2.1	3.3	4.2	2.1	4.2	2.1	4.2	
			2 V	0.3	0.6	1	0.3	1	0.3	1	
V <sub>T</sub>			4.5 V	0.9	1.6	2.45	0.9	2.45	0.9	2.45	V
			6 V	1.2	2	3.2	1.2	3.2	1.2	3.2	
			2 V	0.2	0.6	1.2	0.2	1.2	0.2	1.2	
V <sub>T+</sub> – V <sub>T</sub>			4.5 V	0.4	0.9	2.1	0.4	2.1	0.4	2.1	V
			6 V	0.5	1.3	2.5	0.5	2.5	0.5	2.5	
lį	$V_I = V_{CC}$ or 0	•	6 V		±0.1	±100		±1000		±1000	nA
Icc	$V_I = V_{CC}$ or 0,	IO = 0	6 V			2		40		20	μΑ
Ci			2 V to 6 V		3	10		10		10	pF

# switching characteristics over recommended operating free-air temperature range, $C_L$ = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	ROM TO		T,	ղ = 25°C	;	SN54I	HC14	SN74F	HC14	UNIT
	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
		2 V		55	125		190		155			
t <sub>pd</sub>	Α	Υ	4.5 V		12	25		38		31	ns	
		6 V		11	21		32		26			
			2 V		38	75		110		95		
t <sub>t</sub>	Y	Υ	4.5 V		8	15		22		19	ns	
			6 V		6	13		19		16		

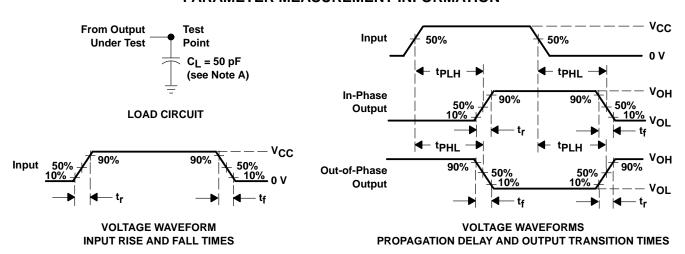
#### operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance per inverter	No load	20	pF



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#### PARAMETER MEASUREMENT INFORMATION



NOTES: A.  $C_L$  includes probe and test-fixture capacitance.

- B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \ \Omega$ ,  $t_f = 6 \ ns$ ,  $t_f = 6 \ ns$ .
- C. The outputs are measured one at a time with one input transition per measurement.
- D. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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